

200V N-Channel MOSFET

Description

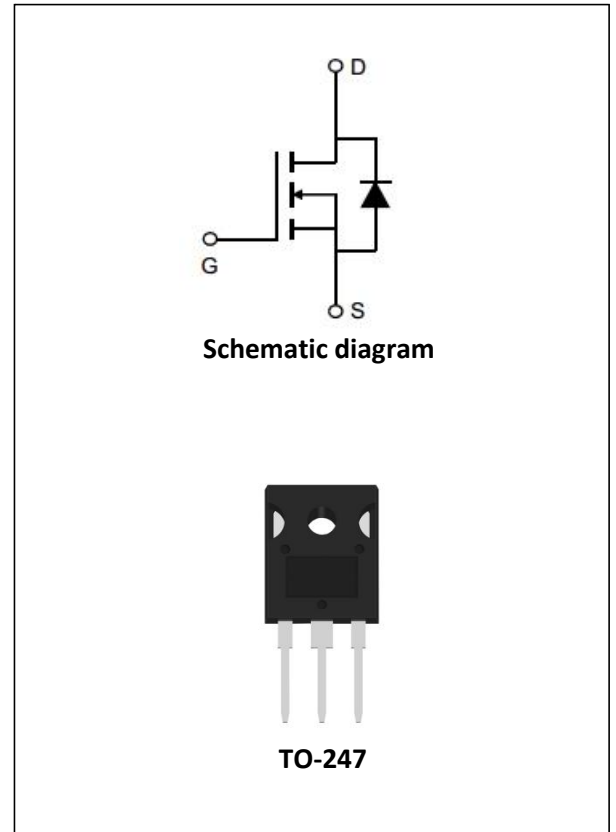
IRFP250N, the silicon N-channel Enhanced MOSFETs, is obtained by advanced MOSFET technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor is suitable device for SMPS, high speed switching and general purpose applications

FEATURES

- ① Proprietary New Planar Technology
- ② $R_{DS(ON),typ.} = 70m\ \Omega @ V_{GS} = 10V$
- ③ Low Gate Charge Minimize Switching Loss
- ④ Fast Recovery Body Diode

APPLICATIONS

- ① DC-DC Converters
- ② DC-AC Inverters for UPS
- ③ SMPS and Motor controls



Package Marking And Ordering Information:

Ordering Codes	Package	Product Code	Packing
IRFP250N	TO-247	IRFP250N	Tube

Absolute Maximum Ratings TC = 25°C, unless otherwise noted				
Parameter	Symbol	Value		Unit
		TO-247		
Drain-Source Voltage	V_{DSS}	200		V
Continuous Drain Current	I_D	30		A
Pulsed Drain Current	I_{DM} (note1)	160		A
Gate-Source Voltage	V_{GSS}	±20		V
Single Pulse Avalanche Energy	E_{AS} (note1)	191		mJ
Avalanche Current	I_{AS} (note1)	31		A
Repetitive Avalanche Energy	E_{AR} (note1)	124		mJ
Power Dissipation (TC = 25°C)	P_D	63.7	104	W



Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55~+150				°C
Thermal Resistance						
Parameter	Symbol	Value			Unit	
		TO-247				
Thermal Resistance, Junction-to-Case	R_{thJC}	1.2			°C/W	
Thermal Resistance, Junction-to-Ambient	R_{thJA}	60				
Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	200	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=200V, V_{GS} = 0V, T_J = 25^\circ\text{C}$	--	--	1	μA
		$V_{DS}=200V, V_{GS}=0V, T_J = 125^\circ\text{C}$	--	--	100	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	--	4.0	V
Drain-Source On-Resistance (Note4)	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 20A$	--	0.07	0.08	Ω
Forward Transconductance (Note4)	g_{fs}	$V_{DS} = 25V, I_D = 20A$	--	16	--	S
Dynamic						
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=25V, f=1.0MHz$	--	2800	--	pF
Output Capacitance	C_{oss}		--	355	--	
Reverse Transfer Capacitance	C_{rss}		--	101	--	
Total Gate Charge	Q_g	$V_{DD} = 160V, I_D = 30A,$	--	154	--	nC
Gate-Source Charge	Q_{gs}		--	13	--	
Gate-Drain Charge	Q_{gd}		--	58	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=160V, I_D=30A, V_{GS} = 15V. R_G=25\Omega$	--	46	--	ns
Turn-on Rise Time	t_r		--	54	--	
Turn-off Delay Time	$t_{d(off)}$		--	360	--	
Turn-off Fall Time	t_f		--	96	--	
Drain-Source Body Diode Characteristics						
Continuous Source Current	I_{SD}		--	--	30	



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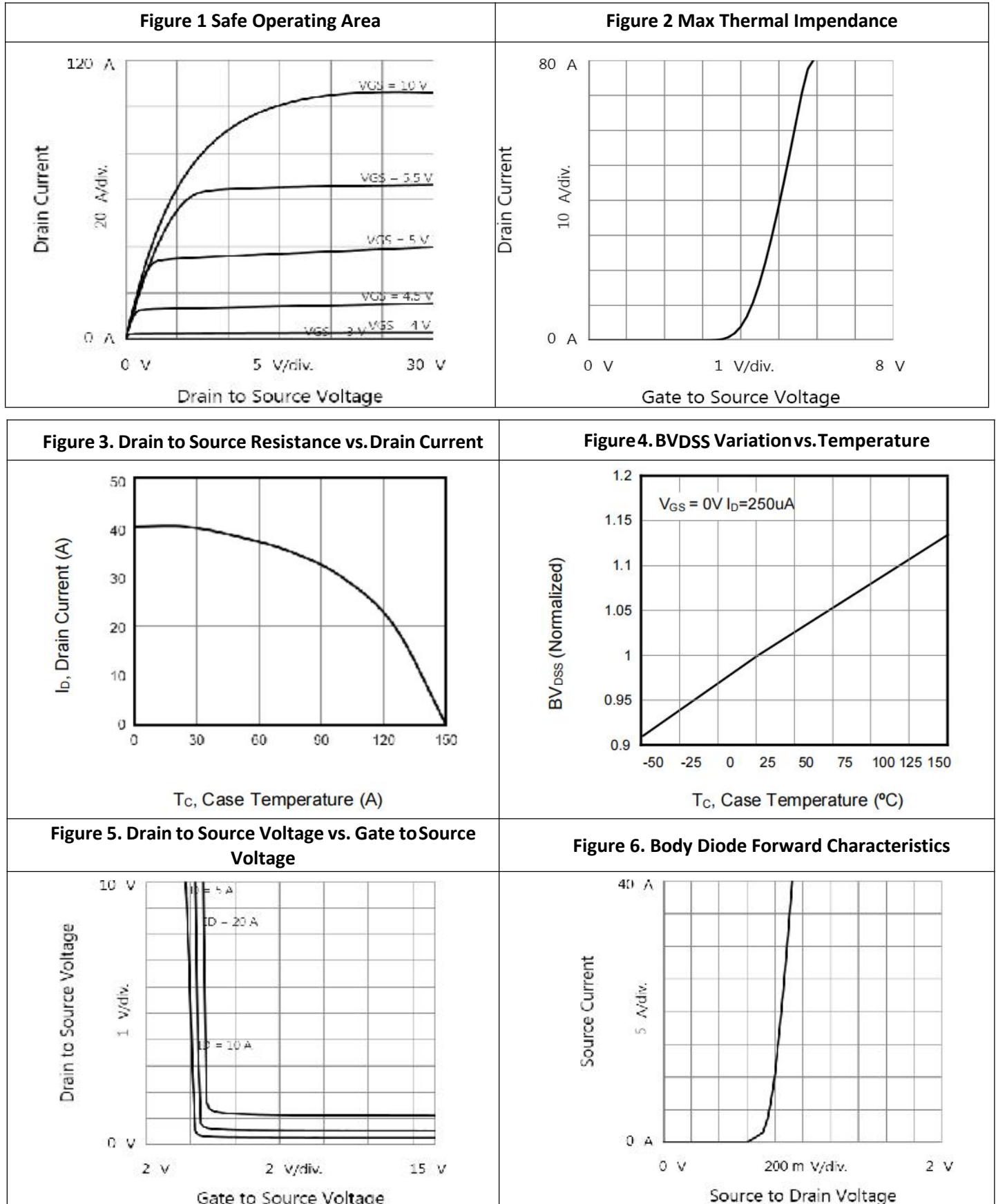
IRFP250N

Pulsed Source Current	I_{SM}	Integral PN-diode in MOSFET	--	--	160	A
Body Forward Voltage	V_{SD}	$I_S = 20A, V_{GS} = 0V$	--	--	1.4	V
Reverse Recovery Time	t_{rr}	$V_{GS} = 0V, I_F = 10A,$ $di_F/dt = 100A/\mu s$	--	152	--	ns
Reverse Recovery Charge	Q_{rr}		--	1	--	μC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. $L=1mH, V_{DD}=30V, R_G=25\Omega, \text{Starting } T_J=25\text{ }^\circ C$
3. Pulse Test: Pulse width $\leq 300\mu s, \text{Duty Cycle}\leq 1\%$

Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted



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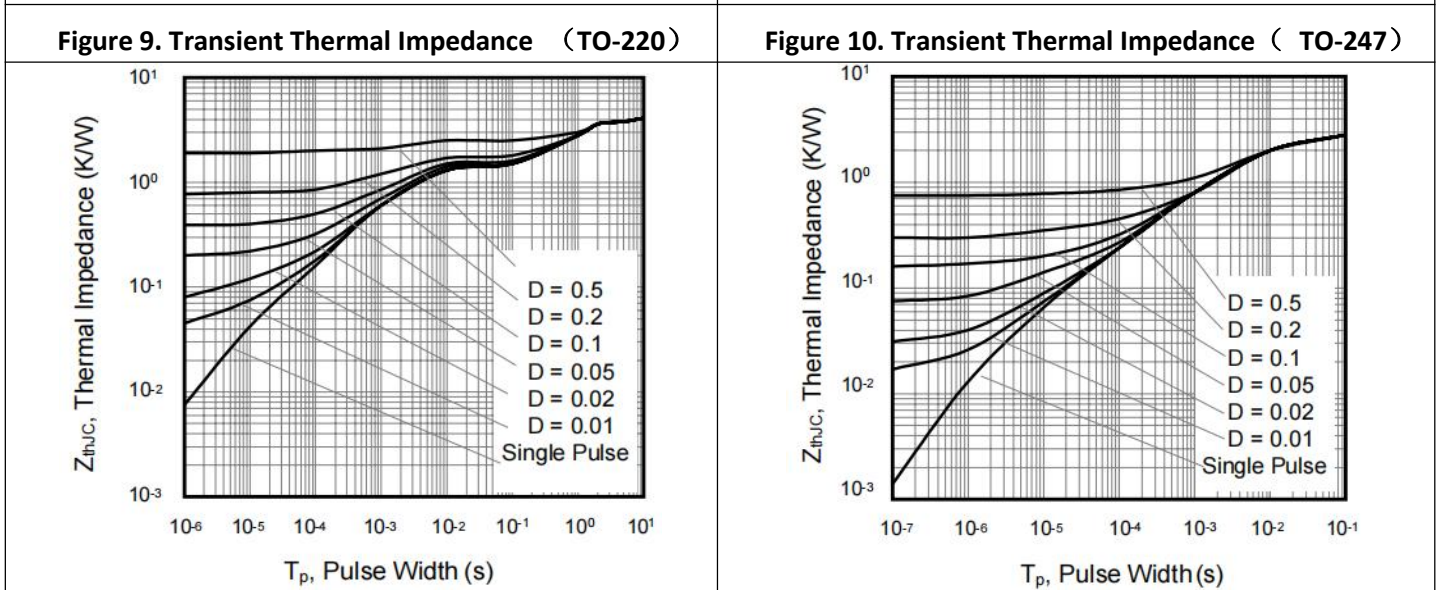
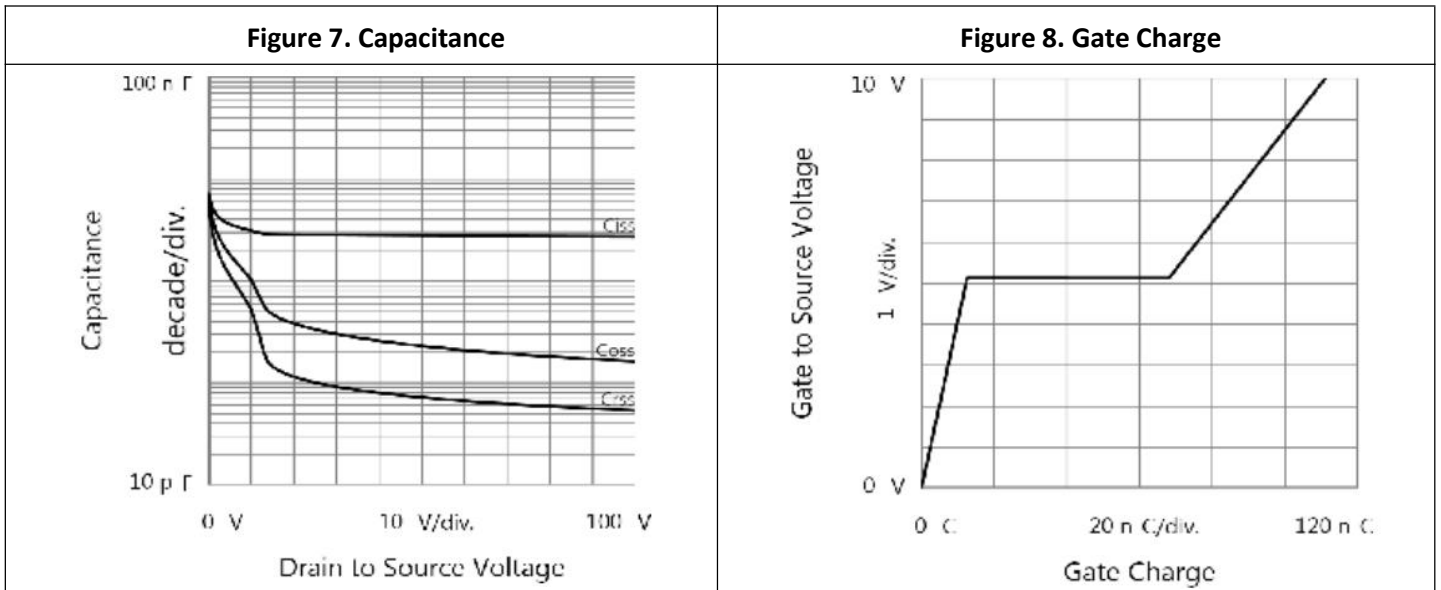


Figure A: Gate Charge Test Circuit and Waveform

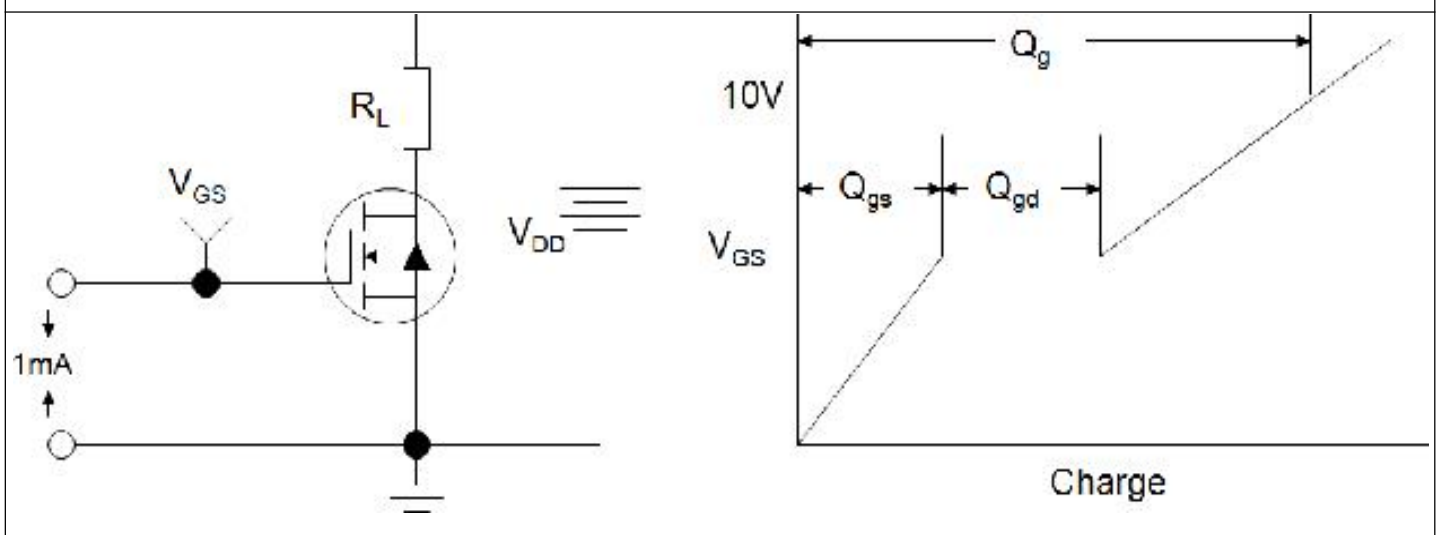


Figure B: Resistive Switching Test Circuit and Waveform

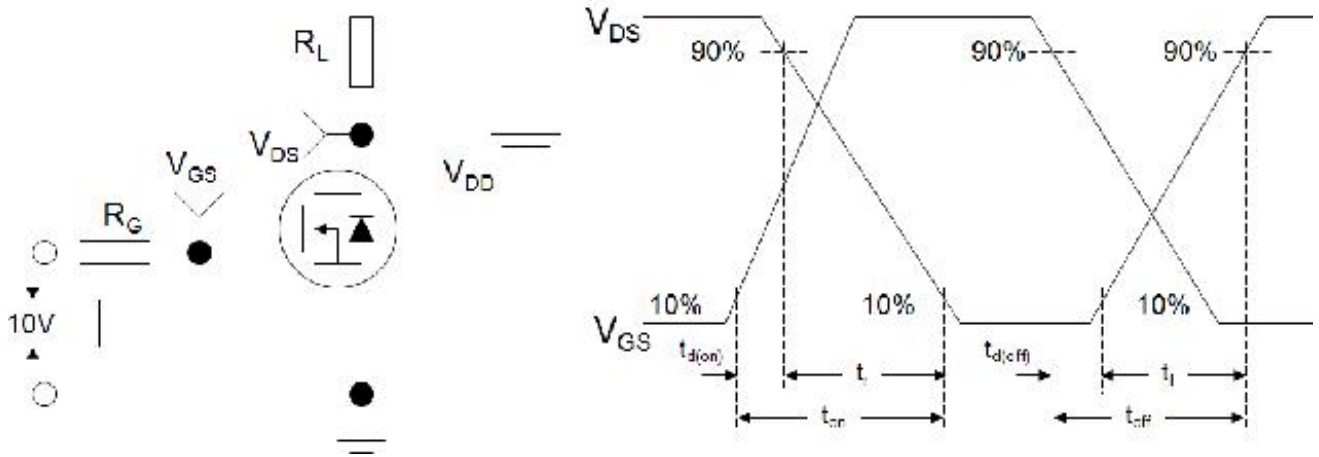
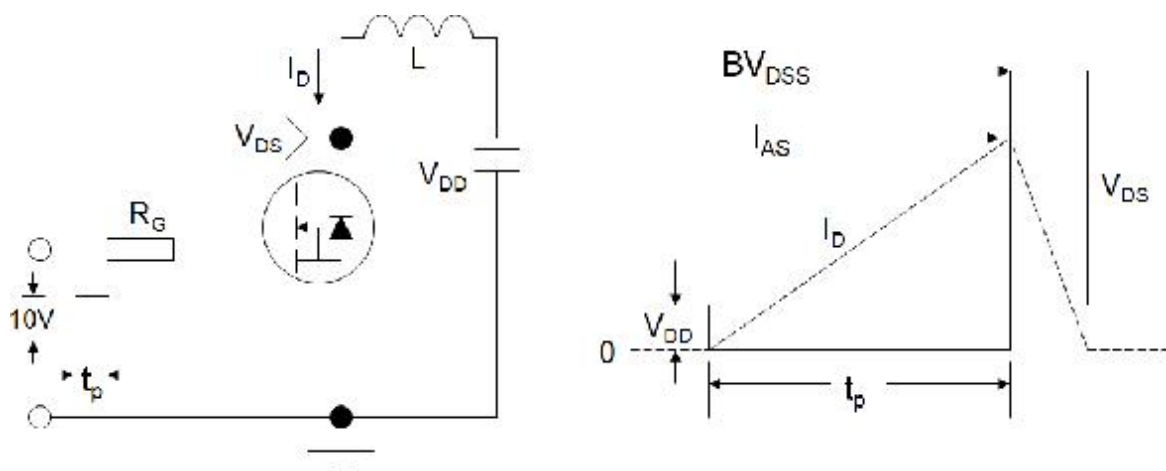
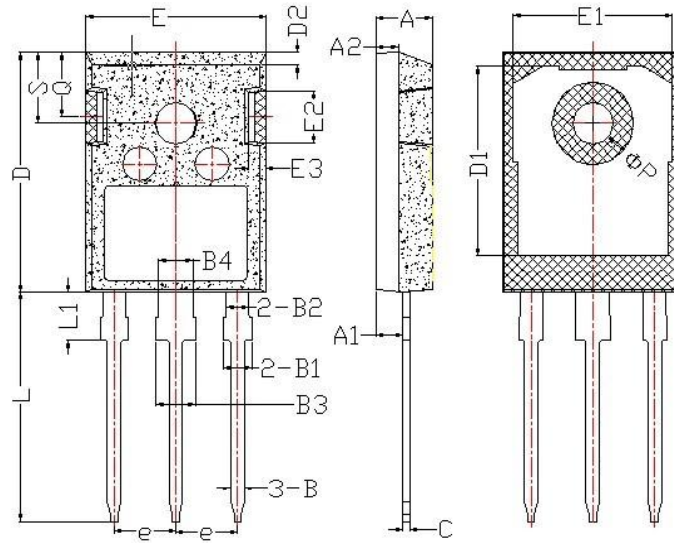


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Package Description



Items	Values(mm)	
	MIN	MAX
A	4.6	5.2
A1	2,2	2.6
B	0.9	1.4
B1	1.75	2.35
B2	1.75	2.15
B3	2.8	3.35
B4	2.8	3.15
C	0.5	0.7
D	20.60	21.30
D1	16	18
E	15.5	16.10
E1	13	14.7
E2	3.80	5.3
E3	0.8	2.60
e	5.2	5.7
L	19	20.5
L1	3.9	4.6
ΦP	2.5	3.70
Q	5.2	6.00
S	5.8	6.6

TO-247 Package



NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change without prior notice.

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